

MOSFET – N-Channel, Shielded Gate, POWERTRENCH[®] 100 V, 7.5 A, 103 mΩ

FDMC86116LZ, FDMC86116LZ-L701

General Description

This N-Channel logic Level MOSFETs are produced using **onsemi**'s advanced POWERTRENCH process that incorporates Shielded Gate technology. This process has been optimized for the on-state resistance and yet maintain superior switching performance. G-S zener has been added to enhance ESD voltage level.

Features

- Max $R_{DS(on)} = 103 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 3.3 \text{ A}$
- Max $R_{DS(on)} = 153 \text{ m}\Omega$ at $V_{GS} = 4.5 \text{ V}$, $I_D = 2.7 \text{ A}$
- HBM ESD Protection Level > 3 kV Typical (Note 1)
- 100% UIL Tested
- These Devices are Pb-Free and are RoHS Compliant

Applications

• DC-DC Conversion



WDFN8 3.3x3.3, 0.65P CASE 511DR FDMC86116LZ





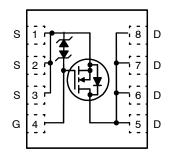
Bottom

Top Bottom **WDFN8 3.3x3.3, 0.65P**

CASE 511DQ

FDMC86116LZ-L701

PIN ASSIGNMENT



MARKING DIAGRAM

AXYKK FDMC 86116Z FDMC 86116Z ALYW

FDMC86116LZ

FDMC86116LZ-L701

FDMC86116Z = Specific Device Code
A = Assembly Site
XY = 2-Digit Date Code

KK = 2-Digit Lot Run Traceability Code

L = Wafer Lot Number YW = Assembly Start Week

ORDERING INFORMATION

See detailed ordering and shipping information on page 6 of this data sheet.

The diode connected between gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

MOSFET MAXIMUM RATINGS ($T_A = 25^{\circ}C$ unless otherwise noted)

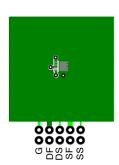
Symbol	Parameter			Ratings	Unit
V _{DS}	Drain to Source Voltage			100	V
V _{GS}	Gate to Source Voltage			±20	V
I _D	Drain Current	Continuous	T _C = 25°C	7.5	Α
		Continuous (Note 3a)	T _A = 25°C	3.3	
		Pulsed	•	15	
E _{AS}	Single Pulse Avalanche Energy (Note 2)		12	mJ	
P_{D}	Power Dissipation $T_C = 25^{\circ}C$		T _C = 25°C	19	W
	Power Dissipation (Note 3a) T _A = 25°C			2.3	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected. 2. Starting $T_J = 25^{\circ}C$; N-ch: L = 1 mH, $I_{AS} = 5.0$ A, $V_{DD} = 90$ V, $V_{GS} = 10$ V.

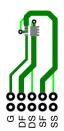
THERMAL CHARACTERISTICS

Symbol	Parameter	Ratings	Unit
Rejc	Thermal Resistance, Junction to Case		°C/W
RθJA	Thermal Resistance, Junction to Ambient (Note 3a)	53	

3. $R_{\theta JA}$ is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined bythe user's board design.



a. 53°C/W when mounted on a 1 in² pad of 2 oz copper



b. 125°C/W when mounted on a minimum pad of 2 oz copper

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted)

Parameter	Test Conditions	Min	Тур	Max	Unit
CTERISTICS					
Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	100	-	-	V
Breakdown Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25°C	-	73	-	mV/°C
Zero Gate Voltage Drain Current	V _{DS} = 80 V, V _{GS} = 0 V	-	_	1	μΑ
Gate to Source Leakage Current	V _{GS} = ±20 V, V _{DS} = 0 V	-	_	±10	μΑ
CTERISTICS					
Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	1.0	1.8	2.2	V
Gate to Source Threshold Voltage Temperature Coefficient	I _D = 250 μA, referenced to 25°C	-	-6	-	mV/°C
Static Drain to Source On Resistance	V _{GS} = 10 V, I _D = 3.3 A	-	79	103	mΩ
	V _{GS} = 4.5 V, I _D = 2.7 A	-	105	153	1
	V _{GS} = 10 V, I _D = 3.3 A, T _J = 125°C	-	136	178	1
Forward Transconductance	V _{DS} = 5 V, I _D = 3.3 A	-	11	-	S
HARACTERISTICS					
Input Capacitance	V _{DS} = 50 V, V _{GS} = 0 V, f = 1 MHz	_	232	310	pF
Output Capacitance	1 1	_	45	60	pF
Reverse Transfer Capacitance	1	-	2.4	5	pF
Gate Resistance		_	0.7	-	Ω
CHARACTERISTICS					
Turn-On Delay Time	$V_{DD} = 50 \text{ V}, I_D = 3.3 \text{ A}, V_{GS} = 10 \text{ V},$	-	4.5	10	ns
Rise Time	$R_{GEN} = 6 \Omega$	-	1.3	10	ns
Turn-Off Delay Time	1 1	-	10	20	ns
Fall Time	1	-	1.4	10	ns
Total Gate Charge	V _{GS} = 0 V to 10 V, V _{DD} = 50 V, I _D = 3.3 A	_	4	6	nC
Total Gate Charge	V _{GS} = 0 V to 4.5 V, V _{DD} = 50 V, I _D = 3.3 A	-	2	3	nC
Total Gate Charge	V _{DD} = 50 V, I _D = 3.3 A	-	0.8	-	nC
Gate to Drain "Miller" Charge	1 1	-	0.7	-	nC
IRCE DIODE CHARACTERISTICS			•		
Source to Drain Diode Forward Voltage	V _{GS} = 0 V, I _S = 3.3 A (Note 4)	-	0.85	1.3	V
	V _{GS} = 0 V, I _S = 2 A (Note 4)	-	0.82	1.2	1
Reverse Recovery Time	I _F = 3.3 A, di/dt = 100 A/μs	-	33	54	ns
Reverse Recovery Charge	1		23	38	nC
	Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate to Source Leakage Current CTERISTICS Gate to Source Threshold Voltage Gate to Source Threshold Voltage Temperature Coefficient Static Drain to Source On Resistance Forward Transconductance HARACTERISTICS Input Capacitance Output Capacitance Gate Resistance CHARACTERISTICS Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Total Gate Charge Total Gate Charge Gate to Drain "Miller" Charge RCE DIODE CHARACTERISTICS Source to Drain Diode Forward Voltage	CTERISTICS Drain to Source Breakdown Voltage $I_D = 250 \mu A$, $V_{GS} = 0 \text{ V}$ Breakdown Voltage Temperature Coefficient $I_D = 250 \mu A$, referenced to $25^{\circ}C$ Zero Gate Voltage Drain Current $V_{DS} = 80 \text{ V}$, $V_{DS} = 0 \text{ V}$ Gate to Source Leakage Current $V_{GS} = \pm 20 \text{ V}$, $V_{DS} = 0 \text{ V}$ CTERISTICS Gate to Source Threshold Voltage $I_D = 250 \mu A$, referenced to $25^{\circ}C$ Gate to Source Threshold Voltage $I_D = 250 \mu A$, referenced to $25^{\circ}C$ Gate to Source On Resistance $I_D = 250 \mu A$, referenced to $25^{\circ}C$ Emperature Coefficient $I_D = 250 \mu A$, referenced to $25^{\circ}C$ Static Drain to Source On Resistance $I_D = 250 \mu A$, referenced to $25^{\circ}C$ Forward Transconductance $V_{GS} = 10 \text{ V}$, $I_D = 3.3 \text{ A}$ HARACTERISTICS $I_D = 3.3 A$, $I_D = 2.7 A$ Input Capacitance $I_D = 3.3 A$ Reverse Transfer Capacitance $I_D = 3.3 A$ Gate Resistance $I_D = 3.3 A$ Turn-On Delay Time $I_D = 50 \text{ V}$, $I_D = 3.3 A$, $I_D = 3.3 A$ Rise Time $I_D = 3.3 A$ Total Gate Charge $I_D = 3.3 A$ Total Gate Charge $I_D = 3.3 A$ Total Gate Charge	CTERISTICS Drain to Source Breakdown Voltage $I_D = 250 \mu A$, $V_{GS} = 0 V$ 100 Breakdown Voltage Temperature Coefficient $I_D = 250 \mu A$, referenced to 25°C – Zero Gate Voltage Drain Current $V_{DS} = 80 \text{ V}$, $V_{GS} = 0 \text{ V}$ – Gate to Source Leakage Current $V_{GS} = \pm 20 \text{ V}$, $V_{DS} = 0 \text{ V}$ – CTERISTICS Use a V_{DS}, I_D = 250 μA 1.0 Gate to Source Threshold Voltage Temperature Coefficient I_D = 250 μA, referenced to 25°C – Static Drain to Source On Resistance V_{GS} = 10 V, I_D = 3.3 A – V _{GS} = 10 V, I_D = 3.3 A – – V _{GS} = 10 V, I_D = 3.3 A – – Forward Transconductance V _{DS} = 5 V, I_D = 3.3 A – HARACTERISTICS Input Capacitance – Input Capacitance V _{DS} = 50 V, V _{GS} = 0 V, f = 1 MHz – Reverse Transfer Capacitance – – Gate Resistance – – CHARACTERISTICS Turn–On Delay Time V _{DD} = 50 V, I _D = 3.3 A, V _{GS} = 10 V, R _{GS} = 10 V, R _{GS} = 6 Ω – Turn–Off Delay Time V _{DS} = 0 V to 10 V, V _{DD} = 50 V, I _D = 3.3 A – –	CTERISTICS Drain to Source Breakdown Voltage $I_D = 250 \mu A, V_{GS} = 0 V$ 100 - Breakdown Voltage Temperature Coefficient $I_D = 250 \mu A, V_{GS} = 0 V$ - - 73 Zero Gate Voltage Drain Current $V_{DS} = 80 V, V_{DS} = 0 V$ - - - Gate to Source Leakage Current $V_{GS} = \pm 20 V, V_{DS} = 0 V$ - - - TERISTICS Gate to Source Threshold Voltage Temperature Coefficient $V_{GS} = \pm 20 V, V_{DS} = 0 V$ 1.0 1.8 Gate to Source Threshold Voltage Temperature Coefficient $I_D = 250 \mu A, \text{referenced to } 25^{\circ}\text{C}$ - - -6 - -6 - -6 - -6 - -6 - -6 - -6 - -6 - -6 - -6 - -6 - -6 - -6 - -6 - -6 - -6 - -6 - -7 9 - -5 -7 -7 -7 -7 -7 -7 </td <td>CTERISTICS Drain to Source Breakdown Voltage ID = 250 μA, VGS = 0 V 100 - - Breakdown Voltage Temperature Coefficient ID = 250 μA, referenced to 25°C - 73 - Zero Gate Voltage Drain Current VDS = 80 V, VGS = 0 V - - - 1 Gate to Source Leakage Current VGS = ±20 V, VDS = 0 V - - ±10 TERISTICS Gate to Source Threshold Voltage VGS = VDS, ID = 250 μA 1.0 1.8 2.2 Gate to Source Threshold Voltage ID = 250 μA, referenced to 25°C -</td>	CTERISTICS Drain to Source Breakdown Voltage ID = 250 μA, VGS = 0 V 100 - - Breakdown Voltage Temperature Coefficient ID = 250 μA, referenced to 25°C - 73 - Zero Gate Voltage Drain Current VDS = 80 V, VGS = 0 V - - - 1 Gate to Source Leakage Current VGS = ±20 V, VDS = 0 V - - ±10 TERISTICS Gate to Source Threshold Voltage VGS = VDS, ID = 250 μA 1.0 1.8 2.2 Gate to Source Threshold Voltage ID = 250 μA, referenced to 25°C -

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: Pulse Width < 300 µs, Duty cycle < 2.0%.

TYPICAL CHARACTERISTICS (T. J = 25°C UNLESS OTHERWISE NOTED)

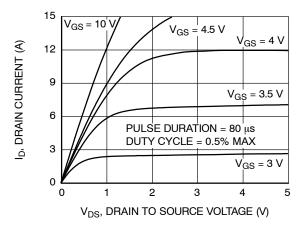


Figure 1. On Region Characteristics

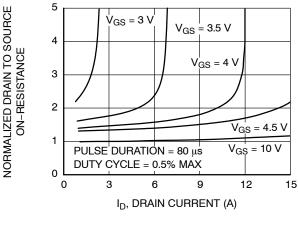


Figure 2. Normalized On–Resistance vs.
Drain Current and Gate Voltage

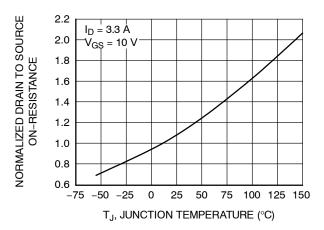


Figure 3. Normalized On Resistance vs. Junction Temperature

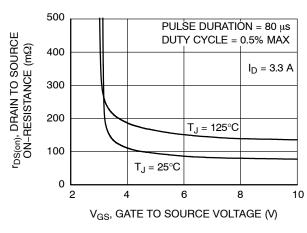


Figure 4. On-Resistance vs. Gate to Source Voltage

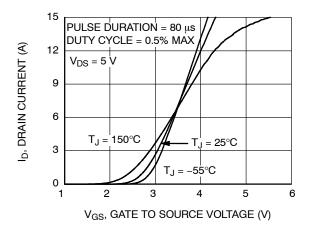


Figure 5. Transfer Characteristics

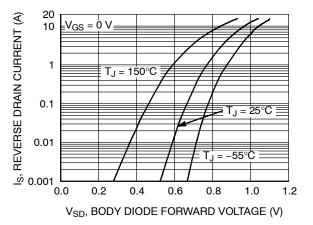


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current

TYPICAL CHARACTERISTICS (CONTINUED)

(T_J = 25°C UNLESS OTHERWISE NOTED)

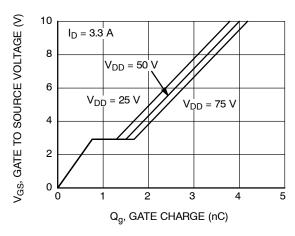


Figure 7. Gate Charge Characteristics

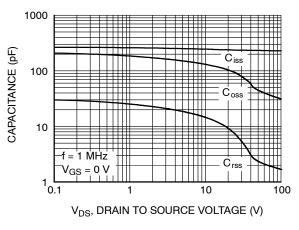


Figure 8. Capacitance vs. Drain to Source Voltage

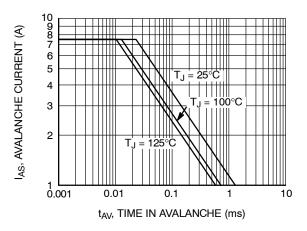


Figure 9. Unclamped Inductive Switching Capability

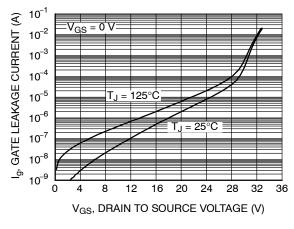


Figure 10. Gate Leakage Current vs. Gate to Source Voltage

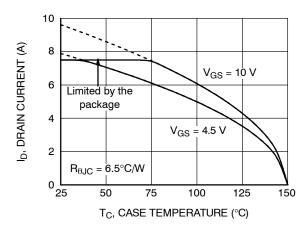


Figure 11. Maximum Continuous Drain Current vs. Case Temperature

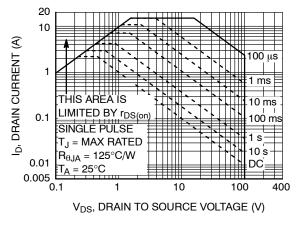


Figure 12. Forward Bias Safe Operating Area

TYPICAL CHARACTERISTICS (CONTINUED)

(T_J = 25°C UNLESS OTHERWISE NOTED)

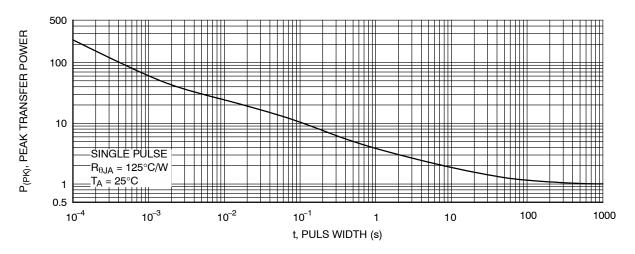


Figure 13. Single pulse Maximum Power Dissipation

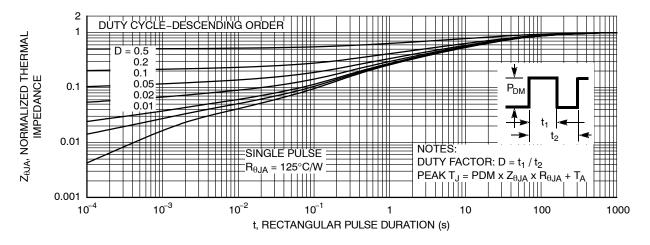


Figure 14. Junction-to-Ambient Transient Thermal Response Curve

ORDERING INFORMATION

Device	Device Marking	Package Type	Reel Size	Tape Width	Shipping [†]
FDMC86116LZ	FDMC86116Z	WDFN8 3.3x3.3, 0.65P Power 33 (Pb-Free)	13"	12 mm	3000 / Tape & Reel
FDMC86116LZ-L701	FDMC86116Z	WDFN8 3.3x3.3, 0.65P Power 33 (Pb-Free)	13"	12 mm	3000 / Tape & Reel

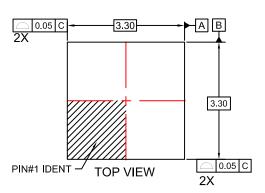
[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

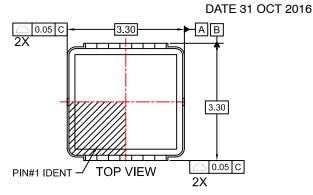
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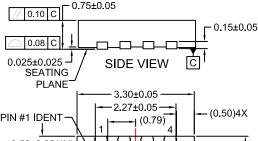


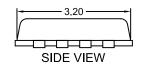
WDFN8 3.3x3.3, 0.65P

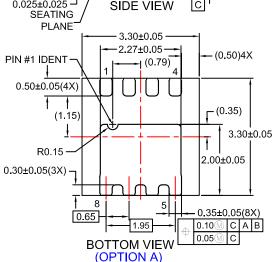
CASE 511DQ ISSUE O

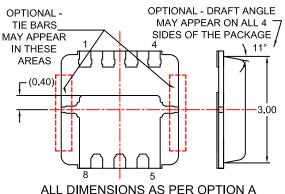


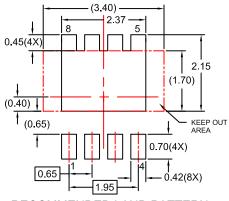












UNLESS SPECIFIED BOTTOM VIEW (OPTION B)

RECOMMENDED LAND PATTERN

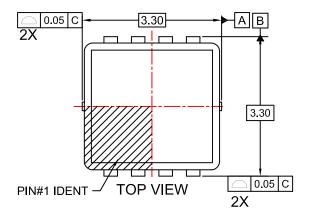
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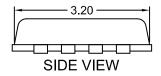
WDFN8 3.3X3.3, 0.65P **DESCRIPTION:** PAGE 1 OF 2

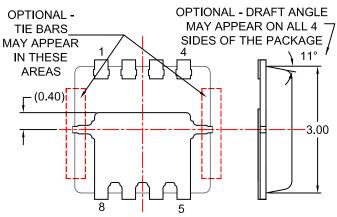
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WDFN8 3.3x3.3, 0.65P CASE 511DQ ISSUE O

DATE 31 OCT 2016







ALL DIMENSIONS AS PER OPTION A
UNLESS SPECIFIED
BOTTOM VIEW
(OPTION C)

NOTES:

- A. PACKAGE DOES NOT FULLY CONFORM TO JEDEC REGISTRATION MO-240.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
- D. LAND PATTERN RECOMMENDATION IS EXISTING INDUSTRY LAND PATTERN
- E. DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. BURRS OR MOLD FLASH SHALL NOT EXCEED 0.10MM.

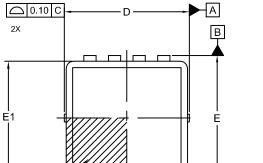
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DESCRIPTION:	WDFN8 3.3X3.3, 0.65P		PAGE 2 OF 2	

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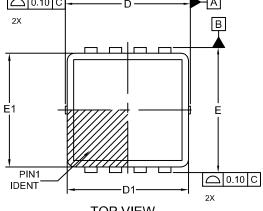
PACKAGE DIMENSIONS

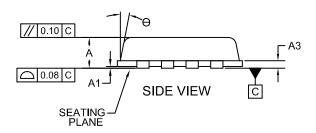
WDFN8 3.3x3.3, 0.65P CASE 511DR **ISSUE B**

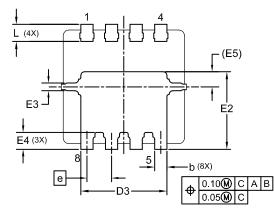
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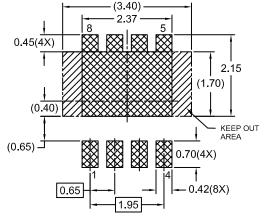


BOTTOM VIEW

NOTES:

- A. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
- B. SEATING PLANE IS DEFINED BY TERMINAL TIPS ONLY
- C. BODY DIMENSIONS DO NOT INCLUDE MOLD FLASH PROTRUSIONS NOR GATE BURRS. MOLD FLASH PROTRUSION OR GATE BURR DOES NOT EXCEED 0.150MM.

DIM	MILLIMETERS			
DIM	MIN	NOM	MAX	
Α	0.70	0.75	0.80	
A1	0.00	ı	0.05	
А3	0.15	0.20	0.25	
b	0.27	0.32	0.37	
D	3.20	3.30	3.40	
D1	3.10	3.20	3.30	
D3	2.17	2.27	2.37	
Е	3.20	3.30	3.40	
E1	2.90	3.00	3.10	
E2	1.95	2.05	2.15	
E3	0.15	0.20	0.25	
E4	0.30	0.40	0.50	
E5	0.40 REF			
е	0.65 BSC			
L	0.30	0.40	0.50	
θ	0°	-	12°	



RECOMMENDED LAND PATTERN

*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.

GENERIC MARKING DIAGRAM*



XXXX = Specific Device Code

= Assembly Location

= Year = Work Week

= Pb-Free Package

(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "=", may or may not be present. Some products may not follow the Generic Marking.

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DESCRIPTION:	WDFN8 3.3x3.3, 0.65P		PAGE 1 OF 1	

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